Studies on the Electrical Properties of Tungsten Doped V₂O₅

O. G. PALANNA

Solid State Laboratory, St. Philomena College, Puttur 574215

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The electrical properties of the monophasic $W_*V_2O_5$ samples for $O < x \le 0.03$ (iso-structural with α -V₂O₅) have been investigated. The conduction mechanism of these non-stoichiometric semiconductors involves hopping of electrons through equivalent vanadium lattice sites. It is found from experimental data that W⁶⁺ ions preferentially occupy interstitial positions influencing the electrical properties of the host system.

 $\mathbf{P}_{\text{non-stoichiometric semiconductors of vanadium pentoxide containing a non-integral number of$ *d*-electrons per transition element lattice site are known.

Dissolved impurities can be incorporated into the lattice of V_2O_5 either interstitially or substitutionally or by both ways. Metal (Mⁿ⁺) ions occupy interstitial sites similar to that in the case of the corresponding vanadium bronzes, $M_xV_2O_5$ (ref. 1) for a limited range of x. However, occupation of lattice (vanadium) sites by W⁶⁺ or Mo⁶⁺ ions is reported in mixed oxide bronzes of vanadium^{2,3}, a few doped V_2O_5 lattices^{4,5} and other tungsten-vanadium oxide compounds⁶⁻⁸.

The present investigation aims at examining the influence of the added impurity ions (W^{6+}) upto $x \leq 0.03$, on the solid state properties of the host V_2O_5 lattice under the conditions of their synthesis.

Materials and Methods

Preparation and characterization of the samples — Different samples of $W_x V_2 O_5$ were obtained by the reactions carried out in the molten state at 1120 K for 48 hr between high purity tungsten metal powder and $V_2 O_5$ taken in the desired proportions $(0 < x \le 0.03$, where $x = W/V_2 O_5$). The molten mass of the reaction was cooled to room temperature at a rate of 10°/min, pressed into pellets of desired thickness and sintered at 900 K for a few hours to achieve the maximum packing density.

The compounds were characterized by X-ray powder diffraction technique using Cu K_{α} radiation $(\lambda = 1.517 \text{ Å})$ and nickel filter.

Electrical conductivity measurements — The D.C. electrical conductivity (σ) of the polycrystalline samples was measured between 300 and 875 K through four probe technique. The samples were in the form of sintered compacts ($\approx 85\%$ packing density) of 18 mm diameter and 2 mm thickness.

The Seebeck coefficient (α) was determined between 300 and 875 K by integral method maintaining a temperature gradient of approximately 10 K between the two ends of the sample.

Results and Discussion

The X-ray analysis shows that the gross V_2O_5 structure is maintained for $x \leq 0.03$, called the α -phase^{9,10}; the W⁶⁺ ions are incorporated at welldefined sites of the lattice. Due to similar ionic sizes of W⁶⁺ (0.54 Å) and V⁵⁺ (0.58 Å), substitution or the interstitial occupation does not change the lattice parameter to such an extent as to distort the V_2O_5 structure.

The data on the electrical conductivities (σ) of the samples are presented in Fig. 1. The $W_x V_2 O_5$ compounds, isostructural with α -V₂O₅, are non-stoichiometric semiconductors. The electrical conductance data presented are characteristic of hopping mechanism of conduction. The sign of the Seebeck coefficient (α) is negative and temperature-independent indicating a constant number of charge carriers (electrons). The electron transfer in such compounds takes place by hopping of electrons on equivalent vanadium sites of the lattice. Figs. 1 and 2 show that the electrical conductivities (σ) of the samples increase with increase in x at a given temperature for $x \leq 0.03$, while the value of Seebeck coefficient (α) decreases. However, it is observed that the number of charge carriers do not increase with increase in temperature as to contribute to electrical conductivity. In such cases, the electrical conductivity could be ascribed to thermally activated. mobility of the charge carriers. The temperaturedependence of σ then follows the equation

$$\log_{10} \sigma T = \log_{10} \sigma_0 T - \Delta G^* / 2 \cdot 3KT \qquad \dots (1)$$

where ΔG^* is the free energy of activation for conduction (Table 1). This is further evidenced

TABLE 1-	- Electrical S	Conductance Amples	Data	FOR T	ΉE	
$= W/V_{0}O_{r}$	Seebeck	Electrical	Sire or d	Activat	ion	

$x = W/V_2O_5$	Seebeck coefficient µV° (<i>n</i> -type)	Electrical conductivity, σ (ohm ⁻¹ cm ⁻¹)	Activation energy (eV)
0	-200	1.5×10^{-5}	0.20
0.005	-50	2.86×10^{-2}	0.24
0.01	-48	3·13×10-2	0.24
0.02	-40	3.63×10-2	0.23
0.03	-30	4·17×10-2	0.22



Fig. 1 — Plots of $\log_{10} \sigma T$ versus $10^3/T$ for $W_x V_2 O_5$ samples [Curve 1, x=0.005; curve 2, x=0.01; curve 3, x=0.02; curve 4, x=0.03]



Fig. 2 — Plots of Seebeck coefficient (a) versus $10^{3}/T$ for $W_{x}V_{2}O_{5}$ samples [Curve 1, x=0.005; curve 2, x=0.01; curve 3, x=0.02; curve 4, x=0.03]

by the linearity of $\log_{10} \sigma T$ versus 1/T plots, and temperature-independence of α (Figs. 1 and 2).

Investigation of V2O5, weakly doped with WO3,5, and also of a few mixed oxide bronzes of the type $M_x V_{2-y} W_y O_5^{2,3}$ for x > 0.33, indicated the occupation of lattice sites by the W6+ ions, in each case causing localization of the $3d^1$ electron at one neighbouring vanadium site. This substitution of tungsten ions for vanadium would result in the formation of $W^{6+}-O-V^{4+}$ pairs within the vanadium array of the host lattice. In this case the excess negative charge of the V^{4+} is bound to the excess positive charge of the W6+ and hence does not participate in the current transfer¹¹. In addition, it can be shown that with the increased number of W6+ ions at the vanadium lattice sites, the $V^{4+}-O-V^{5+}$ distance is enhanced for hopping of electron and thus, the conduction takes place through the lattice with higher activation and σ would vary as $\sigma_{v_2 o_3} > \sigma_x \ge \sigma_{0.03}$. This behaviour, however, is not in agreement with the results observed in the present work.

On the contrary, the present investigation of a weakly doped V_2O_5 sample with W⁶⁺ ions indicates that for $O < x \le 0.03$, the incorporated tungsten ions preferentially occupy interstitial/tunnel sites of the host lattice giving rise to an α -phase. This is supported by the following experimental data:

(i) The XRD data indicates that the samples are monophasic and isostructural with V₂O₅ lattice with no appreciable change in the lattice parameters of the unit cell.

(ii) A characteristic IR bands of $V_2O_5^{12}$ is observed which shows no change in the local symmetry and nature of the bonds in the lattice.

(iii) An ESR signal at g = 1.96 is observed with a narrow line width. The narrowing line width at 300 K indicates (a) localization of the *d*-electrons at the vanadium sites and (b) hopping mechanism of d-electrons13.

(iv) The electrical conductance (σ) and Seebeck coefficient (α) of the samples change as a result of the incorporation of W⁶⁺ ions by a few orders of magnitude depending on the mode of addition and the amount of impurity (W6+) present. Figs. 1

and 2 show that σ values follow the order: $\sigma_{v_{2}o_{5}} < \sigma_{x} \leq \sigma_{0.03}$, while the α value decreases due to the increased number of electrons at a given temperature.

The results of the present investigation indicate that in the system $W_x V_2 O_5$, a number of charge carriers (electrons) per formula unit occupy d-states of vanadium which is empty $(3d^{\circ})$ in the stoichio-metric V_2O_5 . A number of localised, yet mobile $3d^1$ centres are created within an array of vanadium sites. When W6+ ions occupy the interstitial sites of the host lattice, σ is expected to increase enormously. The experimental data obtained in the present work show that $\sigma_{v_2o_5} < \sigma_x \leq \sigma_{0.03}$ for the temperature limit indicated. Accordingly, a values decrease in the order $\alpha_{v_2 v_5} > \alpha_x \ge \alpha_{0.03}$ due to an increased number of electrons in the $V_2 O_5$ lattice.

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